## **AMENDMENTS TO THE CLAIMS:**

This listing of claims will replace all prior versions, and listing, of claims in the application:

## **LISTING OF CLAIMS:**

1. (Currently Amended) A field emission device (FED) comprising:

a substrate;

a cathode formed over the substrate;

micro-tips having nano-sized surface features, each micro tip micro-tip being of homogenous material, formed in electrical contact with the cathode;

a gate insulation layer with wells each of which a single micro-tip is located in, the gate insulation layer formed over the substrate; and

a gate electrode with gates aligned with the wells such that each of the micro-tips is exposed through a corresponding gate, the gate electrode formed on the gate insulation layer.

- 2. (Previously Presented) The field emission device of claim 1, wherein a resistor layer is formed over or beneath the cathode, or a resistor layers are formed over and beneath the cathode.
- 3. (Withdrawn) A method for fabricating a field emission device (FED), comprising:

forming a cathode, a gate insulation layer with wells, and a gate electrode with gates on a substrate in sequence, and forming micro-tips on the cathode exposed by the wells;

forming a carbonaceous polymer layer on the gate electrode, such that the wells having the micro-tips are filled with the carbonaceous polymer layer; and

etching the carbonaceous polymer layer and the surface of the micro-tips by plasma etching using a gas mixture containing  $O_2$  for the carbonaceous polymer layer, and a gas for the micro-tips, as a reaction gas, so that the micro-tips with nano-sized surface features are formed.

- 4. (Withdrawn) The method of claim 3, wherein the carbonaceous polymer layer is formed of polyimide or photoresist.
- 5. (Withdrawn) The method of claim 3, wherein the carbonaceous polymer layer is etched by reactive ion etching (REI).
- 6. (Withdrawn) The method of claim 5, wherein the nano-sized surface features of the micro-tips are adjusted by varying the etch rates of the carbonaceous polymer layer and the micro-tips.
- 7. (Withdrawn) The method of claim 6, wherein the etch rates are adjusted by varying the oxygen-to-the gas for the micro-chips in the reaction gas, plasma power, or plasma pressure during the etching process.

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- 8. (Withdrawn) The method of claim 5, wherein the micro-tips are formed of at least one selected from the group molybdenum (Mo), tungsten (W), silicon (Si) and diamond, and the reaction gas is a gas mixture of  $O_2$  and fluorine-based gas.
- 9. (Withdrawn) The method of claim 8, wherein the reaction gas comprises  $CF_4/O_2$ ,  $SF_6/O_2$ ,  $CF_4/SF_6/O_2$ ,  $CF_4/CHF_3/O_2$ , and  $SF_6/CHF_3/O_2$ .
- 10. (Withdrawn) The method of claim 5, wherein the micro-tips are formed of at least one selected from the group molybdenum (Mo), tungsten (W), silicon (Si) and diamond, and the reaction gas is a gas mixture of  $O_2$  and chlorine-based gas.
- 11. (Withdrawn) The method of claim 10, wherein the reaction gas comprises  $\text{Cl}_2/\text{O}_2$ ,  $\text{CCl}_4/\text{O}_2$ , and  $\text{Cl}_2/\text{CCl}_4/\text{O}_2$ .
- 12. (Withdrawn) A method of fabricating a field emission device (FED) comprising:

providing a substrate;

forming a cathode over the substrate;

forming micro-tips having nano-sized surface features on the cathode;

providing a gate insulation layer with wells each of which a single micro-tip is located in, the gate insulation layer formed over the substrate; and

providing a gate electrode with gates aligned with the wells such that each of the micro-tips is exposed through a corresponding gate, the gate electrode formed on the gate insulation layer.

- 13. (Withdrawn) The method of claim 12, further comprising forming a resistor layer over or beneath the cathode, or forming a resistor layers over and beneath the cathode.
  - 14. (Currently Amended) A field emission device (FED) comprising:

a substrate;

a cathode formed over the substrate;

micro-tips having nano-sized surface features, formed in electrical contact with the cathode;

a gate insulation layer with wells each of which a single micro-tip is located in, the gate insulation layer formed over the substrate;

a gate electrode with gates aligned with the wells such that each of the micro-tips is exposed through a corresponding gate, the gate electrode formed on the gate insulation layer,

wherein said micro-tips having nano-sized surface features is the product of a process of forming a carbonaceous polymer layer on the gate electrode, such that the wells having them the micro-tips are filled with the carbonation polymer layer; and etching the carbonaceous layer and the surface of the micro-tips by plasma etching using a gas mixture  $O_2$  for the carbonaceous polymer layer, and a gas for the micro-tips, as a reaction gas, so that the micro-tips with nano-sized surface features are formed.

15. (Previously Presented) The field emission device of claim 14, wherein a resistor layer is formed over or beneath the cathode, or resistor layers formed over and beneath the cathode.